

Notice of References Cited	Application/Control No. 10/540,688		Applicant(s)/Patent Under Reexamination COENE ET AL.	
	Examiner Dac V. Ha		Art Unit 2611	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,080,293	07-2006	Kim et al.	714/701
*	B	US-6,487,293	11-2002	Sako et al.	380/201
*	C	US-5,778,139	07-1998	Kim, Tae-eung	386/81
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Tan (US 2003/0126545); Jul. 3, 2003; Non-Linear Code-Devison Multiple Access Technology With Improved Detection Algorithms ANd Error Correction Coding
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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